信頼性不足

[Causes/processes involved/keys to judgment]

An adhesive material attached on CCL copper foil prior to copper plating acts as an etching resist to cause the defect. (Before copper plating – etching process)

1-8-1-2 テープ糊短絡/胶带胶迹的短路 / Short by tape adhesive

【特徴】付着糊の下に残った銅箔による複雑形状の 短絡

【特征】在铜箔下面残留胶迹成为复杂形状的短路。

[Characteristics] An irregular-shaped short by copper foil of CCL left under attached adhesive

【原因・判断ポイント・発生工程】積層板銅箔の表面に付着した粘着テープ糊がETレジストとなった為に、めっき銅だけはETされたが、積層板銅箔はETされずに出来たもの(銅めっき前~ET工程)

【原因、判断要点、发生工序】因为铜箔表面附着的胶带胶成为 ET 剂,所以,只有镀铜层被 ET,而层压板铜箔不被 ET 所引起的(镀铜前~ ET 工序)。

[Causes/processes involved/keys to judgment]

Tape adhesive adhered to the copper foil of a CCL acts as an etching resist. Plated copper is etched but the copper foil of CCL is left unetched to cause the defect. (Surface preparation prior to copper plating etching process)



[コメント] 顕微鏡倍率× I注釋] 显微镜倍率 × [Coments] Magnification: ×



[コメント] 顕微鏡倍率× [注释] 显微镜倍率× [Coments] Magnification:×



[コメント] 顕微鏡倍率× I注釋] 显微镜倍率× [Coments] Magnification:×



「コメント」 顕微鏡倍率× 「注释」 显微镜倍率 × [Coments] Magnification: ×

1-8-1-3 CF 接着削短絡/ CF 粘性物的短路 / Short by carrier film adhesive

【特徴】UTCのCF接着物の下に残ったUTC銅 箔短絡

【特征】在 CF 粘性物下面残留 UTC 的短路。

[Characteristics] Short by UTC foil left under carrier film adhesive for UTC.



[コメント] 顕微鏡倍率× 175 [注释] 显微镜倍率×175 [Coments] Magnification: ×175